NLSX5014

4-Bit 100 Mb/s Configurable Dual-Supply Level Translator

The NLSX5014 is a 4-bit configurable dual-supply autosensing bidirectional level translator that does not require a direction control pin. The I/O V_{CC}- and I/O V_L-ports are designed to track two different power supply rails, V_{CC} and V_L respectively. Both the V_{CC} and the V_L supply rails are configurable from 0.9 V to 4.5 V. This allows a logic signal on the V_L side to be translated to either a higher or a lower logic signal voltage on the V_{CC} side, and vice-versa.

The NLSX5014 offers the feature that the values of the V_{CC} and V_L supplies are independent. Design flexibility is maximized because V_L can be set to a value either greater than or less than the V_{CC} supply. In contrast, the majority of competitive auto sense translators have a restriction that the value of the V_L supply must be equal to less than (V_{CC} - 0.4) V.

The NLSX5014 has high output current capability, which allows the translator to drive high capacitive loads such as most high frequency EMI filters. Another feature of the NLSX5014 is that each I/O_V_{Ln} and I/O_V_{CCn} channel can function as either an input or an output.

An Output Enable (EN) input is available to reduce the power consumption. The EN pin can be used to disable both I/O ports by putting them in 3-state which significantly reduces the supply current from both V_{CC} and V_L. The EN signal is referenced to the V_L supply.

Features

- Wide V_{CC}, V_L Operating Range: 0.9 V to 4.5 V
- V_L and V_{CC} are independent
  - V_L may be greater than, equal to, or less than V_{CC}
- High 100 pF Capacitive Drive Capability
- High−Speed with 140 Mb/s Guaranteed Date Rate for V_{CC}, V_L > 1.8 V
- Low Bit−to−Bit Skew
- Overvoltage Tolerant Enable and I/O Pins
- Non−preferential Powerup Sequencing
- Power−Off Protection
- Small packaging: 1.7 mm x 2.0 mm UQFN12, SOIC14, TSSOP14
- These Devices are Pb−Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- Mobile Phones, PDAs, Other Portable Devices

Important Information

- ESD Protection for All Pins:
  - HBM (Human Body Model) > 7000 V

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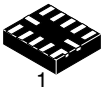
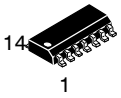
MARKING DIAGRAMS

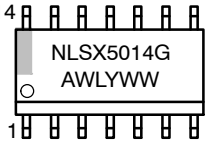


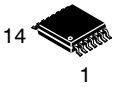
UQFN12
MU SUFFIX
CASE 523AE

M = Date Code
▪ = Pb−Free Package
(Note: Microdot may be in either location)

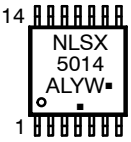


SOIC−14
D SUFFIX
CASE 751A





TSSOP−14
DT SUFFIX
CASE 948G



A	=	Assembly Location
WL, L	=	Wafer Lot
YY, Y	=	Year
WW, W	=	Work Week
G or ▪	=	Pb−Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping†
NLSX5014MUTAG	UQFN12 (Pb−Free)	3000/Tape & Reel
NLSX5014DR2G	SO−14 (Pb−Free)	2500/Tape & Reel
NLSX5014DTR2G	TSSOP14 (Pb−Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

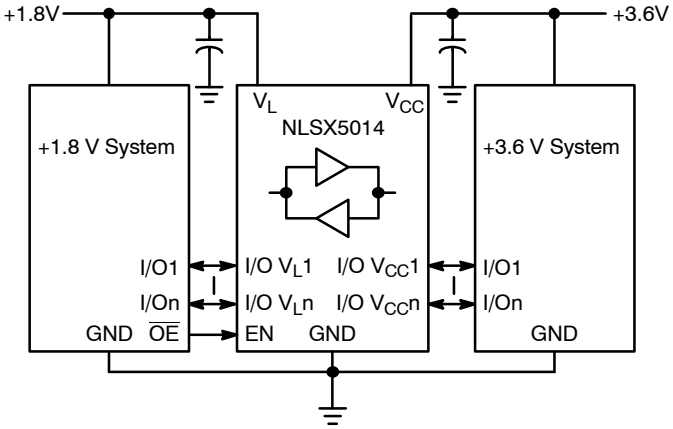


Figure 1. Typical Application Circuit

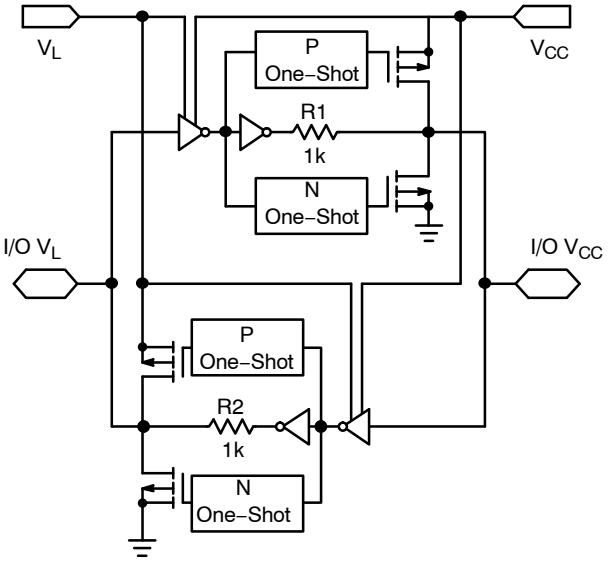


Figure 2. Simplified Functional Diagram (1 I/O Line)

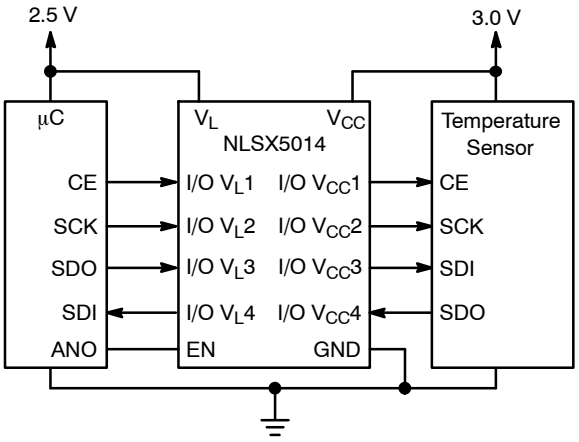


Figure 3. Application Example for $V_L < V_{CC}$

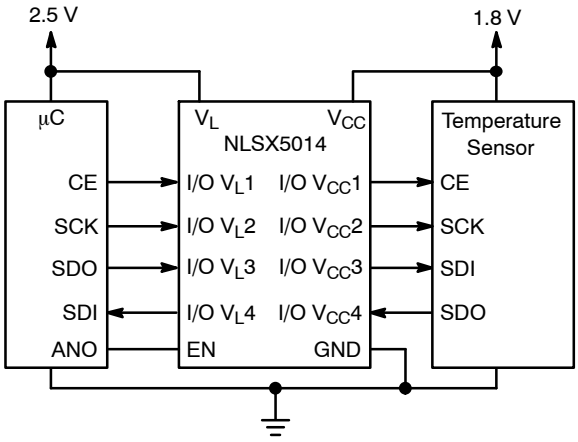


Figure 4. Application Example for $V_L > V_{CC}$

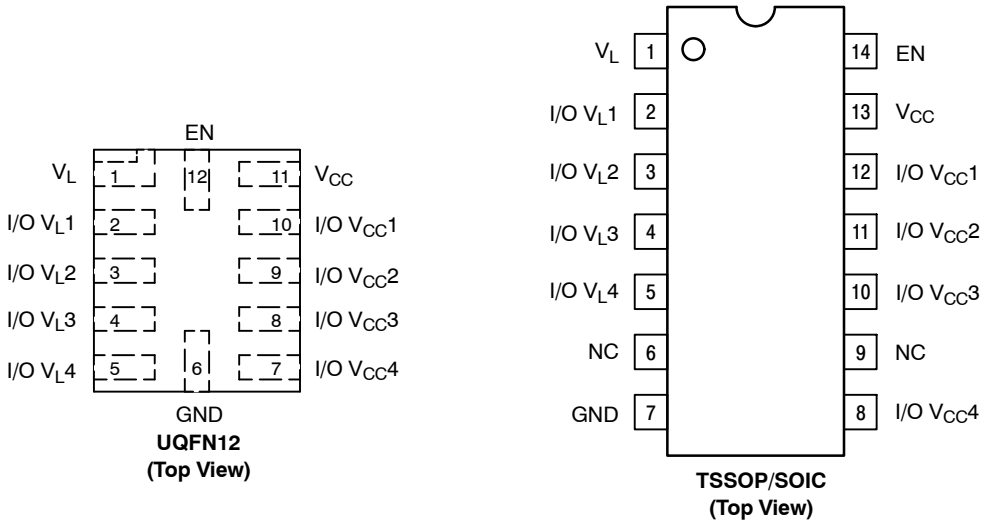


Figure 1. Pin Assignments

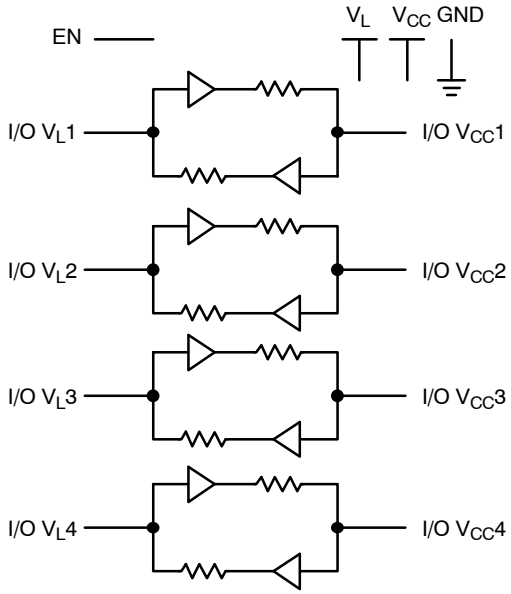


Figure 2. Logic Diagram

PIN ASSIGNMENT

Pins	Description
V_{CC}	V_{CC} Input Voltage
V_L	V_L Input Voltage
GND	Ground
EN	Output Enable
I/O V_{CC}n	I/O Port, Referenced to V_{CC}
I/O V_Ln	I/O Port, Referenced to V_L

FUNCTION TABLE

EN	Operating Mode
L	Hi−Z
H	I/O Buses Connected

MAXIMUM RATINGS

Symbol	Parameter	Value	Condition	Unit
V_{CC}	High−side DC Supply Voltage	−0.5 to +5.5		V
V_L	Low−side DC Supply Voltage	−0.5 to +5.5		V
I/O V_{CC}	V_{CC}−Referenced DC Input/Output Voltage	−0.5 to +5.5		V
I/O V_L	V_L−Referenced DC Input/Output Voltage	−0.5 to +5.5		V
V_I	Enable Control Pin DC Input Voltage	−0.5 to +5.5		V
I_{IK}	DC Input Diode Current	−50	V_I < GND	mA
I_{OK}	DC Output Diode Current	−50	V_O < GND	mA
I_{CC}	DC Supply Current Through V_{CC}	±100		mA
I_L	DC Supply Current Through V_L	±100		mA
I_{GND}	DC Ground Current Through Ground Pin	±100		mA
T_{STG}	Storage Temperature	−65 to +150		°C
	ESD Rating: Machine Model Human Body Model Charged Device Model LU Pass	400 7000 2000 100		V V V mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V_{CC}	High−side Positive DC Supply Voltage	0.9	4.5	V
V_L	Low−side Positive DC Supply Voltage	0.9	4.5	V
V_I	Enable Control Pin Voltage	GND	4.5	V
V_{IO}	Bus Input/Output Voltage: I/O V_{CC} I/O V_L	GND GND	4.5 4.5	V
T_A	Operating Temperature Range	−55	+125	°C
$\Delta t/\Delta V$	Input Transition Rise or Rate V_I, V_{IO} from 30% to 70% of V_{CC}; V_{CC} = 3.3 V ± 0.3 V	0	10	ns

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions (Note 1)	V_{CC} (V) (Note 2)	V_L (V) (Note 3)	–40°C to +85°C			–55°C to +125°C		Unit
					Min	Typ (Note 4)	Max	Min	Max	
V_{IHC}	I/O V_{CC} Input HIGH Voltage		0.9 – 4.5	0.9 – 4.5	2/3 * V_{CC}	–	–	2/3 * V_{CC}	–	V
V_{ILC}	I/O V_{CC} Input LOW Voltage		0.9 – 4.5	0.9 – 4.5	–	–	1/3 * V_{CC}	–	1/3 * V_{CC}	V
V_{IHL}	I/O V_L Input HIGH Voltage		0.9 – 4.5	0.9 – 4.5	2/3 * V_L	–	–	2/3 * V_L	–	V
V_{ILL}	I/O V_L Input LOW Voltage		0.9 – 4.5	0.9 – 4.5	–	–	1/3 * V_L	–	1/3 * V_L	V
V_{IH}	Control Pin Input HIGH Voltage	T_A = +25°C	1.2 – 4.5	1.2 – 4.5	2/3 * V_L	–	–	2/3 * V_L	–	V
V_{IL}	Control Pin Input LOW Voltage	T_A = +25°C	1.2 – 4.5	1.2 – 4.5	–	–	1/3 * V_L	–	1/3 * V_L	V
V_{IH}	Control Pin Input HIGH Voltage	T_A = +25°C	V_{CC} < 1.2	V_L < 1.2	V_L	–	–	V_L	–	V
V_{IL}	Control Pin Input LOW Voltage	T_A = +25°C	V_{CC} < 1.2	V_L < 1.2	–	–	0	–	0	V
V_{OHC}	I/O V_{CC} Output HIGH Voltage	I/O V_{CC} source current = 20 μA	0.9 – 4.5	0.9 – 4.5	0.9 * V_{CC}	–	–	0.9 * V_{CC}	–	V
V_{OLC}	I/O V_{CC} Output LOW Voltage	I/O V_{CC} sink current = 20 μA	0.9 – 4.5	0.9 – 4.5	–	–	0.2	–	0.2	V
V_{OHL}	I/O V_L Output HIGH Voltage	I/O V_L source current = 20 μA	0.9 – 4.5	0.9 – 4.5	0.9 * V_L	–	–	0.9 * V_L	–	V
V_{OLL}	I/O V_L Output LOW Voltage	I/O V_L sink current = 20 μA	0.9 – 4.5	0.9 – 4.5	–	–	0.2	–	0.2	V
I_{QVCC}	V_{CC} Supply Current	EN = V_L, I_O = 0 A, (I/O V_{CC} = 0 V or V_{CC}, I/O V_L = float) or (I/O V_{CC} = float, I/O V_L = 0 V or V_L)	0.9 – 4.5	0.9 – 4.5	–	–	1	–	2.5	μA
I_{QVL}	V_L Supply Current		0.9 – 4.5	0.9 – 4.5	–	–	1	–	2.5	μA
I_{TS-VCC}	V_{CC} Tristate Output Mode Supply Current	T_A = +25°C, EN = 0 V (I/O V_{CC} = 0 V or V_{CC}, I/O V_L = float) or (I/O V_{CC} = float, I/O V_L = 0 V or V_L)	0.9 – 4.5	0.9 – 4.5	–	–	0.5	–	1.5	μA
I_{TS-VL}	V_L Tristate Output Mode Supply Current		0.9 – 4.5	0.9 – 4.5	–	–	0.5	–	1.5	μA
I_{OZ}	I/O Tristate Output Mode Leakage Current	T_A = +25°C, EN = 0V	0.9 – 4.5	0.9 – 4.5	–	–	±1	–	±1.5	μA
I_I	Control Pin Input Current	T_A = +25°C	0.9 – 4.5	0.9 – 4.5	–	–	±1	–	±1	μA
I_{OFF}	Power Off Leakage Current	I/O V_{CC} = 0 to 4.5V, I/O V_L = 0 to 4.5 V	0	0	–	–	1	–	1.5	μA
			0.9 – 4.5	0	–	–	1	–	1.5	
			0	0.9 – 4.5	–	–	1	–	1.5	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. Normal test conditions are V_I = 0 V, $C_{IOVCC} \le 15$ pF and $C_{IOVL} \le 15$ pF, unless otherwise specified.
2. V_{CC} is the supply voltage associated with the I/O V_{CC} port, and V_{CC} ranges from +0.9 V to 4.5 V under normal operating conditions.
3. V_L is the supply voltage associated with the I/O V_L port, and V_L ranges from +0.9 V to 4.5 V under normal operating conditions.
4. Typical values are for V_{CC} = +2.8 V, V_L = +1.8 V and T_A = +25°C. All units are production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed by design.

TIMING CHARACTERISTICS

Symbol	Parameter	Test Conditions (Note 5)	V_{CC} (V) (Note 6)	V_L (V) (Note 7)	–55°C to +125°C			Unit
					Min	Typ (Note 8)	Max	
t_{R-VCC}	I/O V_{CC} Rise Time	C_{IOVCC} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	8.5	nS
			1.8 – 4.5	1.8 – 4.5	–	–	3.5	
t_{F-VCC}	I/O V_{CC} Fall Time	C_{IOVCC} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	8.5	nS
			1.8 – 4.5	1.8 – 4.5	–	–	3.5	
t_{R-VL}	I/O V_L Rise Time	C_{IOVL} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	8.5	nS
			1.8 – 4.5	1.8 – 4.5	–	–	3.5	
t_{F-VL}	I/O V_L Fall Time	C_{IOVL} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	8.5	nS
			1.8 – 4.5	1.8 – 4.5	–	–	3.5	
Z_{OVCC}	I/O V_{CC} One−Shot Output Impedance	(Note 9)	0.9 1.8 4.5	0.9 – 4.5	– – –	37 20 6.0	– – –	Ω
Z_{OVL}	I/O V_L One−Shot Output Impedance	(Note 9)	0.9 1.8 4.5	0.9 – 4.5	– – –	37 20 6.0	– – –	Ω
t_{PD_VL-VCC}	Propagation Delay (Driving I/O V_{CC})	C_{IOVCC} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	35	nS
			1.8 – 4.5	1.8 – 4.5	–	–	10	
		C_{IOVCC} = 30 pF	0.9 – 4.5	0.9 – 4.5	–	–	35	
			1.8 – 4.5	1.8 – 4.5	–	–	10	
		C_{IOVCC} = 50 pF	1.0 – 4.5	1.0 – 4.5	–	–	37	
			1.8 – 4.5	1.8 – 4.5	–	–	11	
		C_{IOVCC} = 100 pF	1.2 – 4.5	1.2 – 4.5	–	–	40	
			1.8 – 4.5	1.8 – 4.5	–	–	13	
t_{PD_VCC-VL}	Propagation Delay (Driving I/O V_L)	C_{IOVL} = 15 pF	0.9 – 4.5	0.9 – 4.5	–	–	35	nS
			1.8 – 4.5	1.8 – 4.5	–	–	10	
		C_{IOVL} = 30 pF	0.9 – 4.5	0.9 – 4.5	–	–	35	
			1.8 – 4.5	1.8 – 4.5	–	–	10	
		C_{IOVL} = 50 pF	1.0 – 4.5	1.0 – 4.5	–	–	37	
			1.8 – 4.5	1.8 – 4.5	–	–	11	
		C_{IOVL} = 100 pF	1.2 – 4.5	1.2 – 4.5	–	–	40	
			1.8 – 4.5	1.8 – 4.5	–	–	13	
t_{SK}	Channel−to−Channel Skew	C_{IOVCC} = 15 pF, C_{IOVL} = 15 pF (Note 9)	0.9 – 4.5	0.9 – 4.5	–	–	0.15	nS
I_{IN_PEAK}	Input Driver Maximum Peak Current	EN = V_L; I/O_V_{CC} = 1 MHz Square Wave, Amplitude = V_{CC}, or I/O_V_L = 1 MHz Square Wave, Amplitude = V_L (Note 9)	0.9 – 4.5	0.9 – 4.5	–	–	5.0	mA

5. Normal test conditions are V_I = 0 V, $C_{IOVCC} \leq$ 15 pF and $C_{IOVL} \leq$ 15 pF, unless otherwise specified.
6. V_{CC} is the supply voltage associated with the I/O V_{CC} port, and V_{CC} ranges from +0.9 V to 4.5 V under normal operating conditions.
7. V_L is the supply voltage associated with the I/O V_L port, and V_L ranges from +0.9 V to 4.5 V under normal operating conditions.
8. Typical values are for V_{CC} = +2.8 V, V_L = +1.8 V and T_A = +25°C. All units are production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed by design.
9. Guaranteed by design.

TIMING CHARACTERISTICS (continued)

Symbol	Parameter		Test Conditions (Note 10)	V_{CC} (V) (Note 11)	V_L (V) (Note 12)	–55°C to +125°C			Unit
						Min	Typ (Note 13)	Max	
t_{EN-VCC}	I/O_V_{CC} Output Enable Time	t_{PZH}	C_{IOVCC} = 15 pF, I/O_V_L = V_L	0.9 – 4.5	0.9 – 4.5	–	–	160	nS
		t_{PZL}	C_{IOVCC} = 15 pF, I/O_V_L = 0 V	0.9 – 4.5	0.9 – 4.5	–	–	130	
t_{EN-VL}	I/O_V_L Output Enable Time	t_{PZH}	C_{IOVL} = 15 pF, I/O_V_{CC} = V_{CC}	0.9 – 4.5	0.9 – 4.5	–	–	160	nS
		t_{PZL}	C_{IOVL} = 15 pF, I/O_V_{CC} = 0 V	0.9 – 4.5	0.9 – 4.5	–	–	130	
$t_{DIS-VCC}$	I/O_V_{CC} Output Disable Time	t_{PHZ}	C_{IOVCC} = 15 pF, I/O_V_L = V_L	0.9 – 4.5	0.9 – 4.5	–	–	210	nS
		t_{PLZ}	C_{IOVCC} = 15 pF, I/O_V_L = 0 V	0.9 – 4.5	0.9 – 4.5	–	–	175	
t_{DIS-VL}	I/O_V_L Output Disable Time	t_{PHZ}	C_{IOVL} = 15 pF, I/O_V_{CC} = V_{CC}	0.9 – 4.5	0.9 – 4.5	–	–	210	nS
		t_{PLZ}	C_{IOVL} = 15 pF, I/O_V_{CC} = 0 V	0.9 – 4.5	0.9 – 4.5	–	–	175	
MDR	Maximum Data Rate		C_{IO} = 15 pF	0.9 – 4.5	0.9 – 4.5	50	–	–	mbps
				1.8 – 4.5	1.8 – 4.5	140	–	–	
			C_{IO} = 30 pF	0.9 – 4.5	0.9 – 4.5	40	–	–	
				1.8 – 4.5	1.8 – 4.5	120	–	–	
			C_{IO} = 50 pF	1.0 – 4.5	1.0 – 4.5	30	–	–	
				1.8 – 4.5	1.8 – 4.5	100	–	–	
			C_{IO} = 100 pF	1.2 – 4.5	1.2 – 4.5	20	–	–	
				1.8 – 4.5	1.8 – 4.5	60	–	–	

10. Normal test conditions are V_I = 0 V, $C_{IOVCC} \le$ 15 pF and $C_{IOVL} \le$ 15 pF, unless otherwise specified.
11. V_{CC} is the supply voltage associated with the I/O V_{CC} port, and V_{CC} ranges from +0.9 V to 4.5 V under normal operating conditions.
12. V_L is the supply voltage associated with the I/O V_L port, and V_L ranges from +0.9 V to 4.5 V under normal operating conditions.
13. Typical values are for V_{CC} = +2.8 V, V_L = +1.8 V and T_A = +25°C. All units are production tested at T_A = +25°C. Limits over the operating temperature range are guaranteed by design.

DYNAMIC POWER CONSUMPTION (T_A = +25°C)

Symbol	Parameter	Test Conditions	V_{CC} (V) (Note 14)	V_L (V) (Note 15)	Typ (Note 16)	Unit
C_{PD_VL}	V_L = Input port, V_{CC} = Output Port	C_{Load} = 0, f = 1 MHz, EN = V_L (outputs enabled)	0.9	4.5	39	pF
			1.5	1.8	20	
			1.8	1.5	17	
			1.8	1.8	14	
			1.8	2.8	13	
			2.5	2.5	14	
			2.8	1.8	13	
			4.5	0.9	19	
	V_{CC} = Input port, V_L = Output Port	C_{Load} = 0, f = 1 MHz, EN = V_L (outputs enabled)	0.9	4.5	37	pF
			1.5	1.8	30	
			1.8	1.5	29	
			1.8	1.8	29	
			1.8	2.8	29	
			2.5	2.5	30	
			2.8	1.8	29	
			4.5	0.9	19	
C_{PD_VCC}	V_L = Input port, V_{CC} = Output Port	C_{Load} = 0, f = 1 MHz, EN = V_L (outputs enabled)	0.9	4.5	29	pF
			1.5	1.8	29	
			1.8	1.5	29	
			1.8	1.8	29	
			1.8	2.8	29	
			2.5	2.5	30	
			2.8	1.8	29	
			4.5	0.9	35	
	V_{CC} = Input port, V_L = Output Port	C_{Load} = 0, f = 1 MHz, EN = V_L (outputs enabled)	0.9	4.5	21	pF
			1.5	1.8	18	
			1.8	1.5	18	
			1.8	1.8	14	
			1.8	2.8	13	
			2.5	2.5	14	
			2.8	1.8	13	
			4.5	0.9	30	

14. V_{CC} is the supply voltage associated with the I/O V_{CC} port, and V_{CC} ranges from +0.9 V to 4.5 V under normal operating conditions.
15. V_L is the supply voltage associated with the I/O V_L port, and V_L ranges from +0.9 V to 4.5 V under normal operating conditions.
16. Typical values are at T_A = +25°C.
17. $C_{PD\ VL}$ and $C_{PD\ VCC}$ are defined as the value of the IC's equivalent capacitance from which the operating current can be calculated for the V_L and V_{CC} power supplies, respectively. $I_{CC} = I_{CC}$ (dynamic) + I_{CC} (static) ≈ I_{CC}(operating) ≈ $C_{PD} \times V_{CC} \times f_{IN} \times N_{SW}$ where $I_{CC} = I_{CC\_VCC} + I_{CC\ VL}$ and N_{SW} = total number of outputs switching.

STATIC POWER CONSUMPTION (T_A = +25°C)

Symbol	Parameter	Test Conditions	V_{CC} (V) (Note 18)	V_L (V) (Note 19)	Typ (Note 20)	Unit
C_{PD_VL}	V_L = Input port, V_{CC} = Output Port	C_{Load} = 0, f = 1 MHz, EN = GND (outputs disabled)	0.9	4.5	0.01	pF
			1.5	1.8	0.01	
			1.8	1.5	0.01	
			1.8	1.8	0.01	
			1.8	2.8	0.01	
			2.5	2.5	0.01	
			2.8	1.8	0.01	
			4.5	0.9	0.01	
	V_{CC} = Input port, V_L = Output Port	C_{Load} = 0, f = 1 MHz, EN = GND (outputs disabled)	0.9	4.5	0.01	pF
			1.5	1.8	0.01	
			1.8	1.5	0.01	
			1.8	1.8	0.01	
			1.8	2.8	0.01	
			2.5	2.5	0.01	
			2.8	1.8	0.01	
			4.5	0.9	0.01	
C_{PD_VCC}	V_L = Input port, V_{CC} = Output Port	C_{Load} = 0, f = 1 MHz, EN = GND (outputs disabled)	0.9	4.5	0.01	pF
			1.5	1.8	0.01	
			1.8	1.5	0.01	
			1.8	1.8	0.01	
			1.8	2.8	0.01	
			2.5	2.5	0.01	
			2.8	1.8	0.01	
			4.5	0.9	0.01	
	V_{CC} = Input port, V_L = Output Port	C_{Load} = 0, f = 1 MHz, EN = GND (outputs disabled)	0.9	4.5	0.01	pF
			1.5	1.8	0.01	
			1.8	1.5	0.01	
			1.8	1.8	0.01	
			1.8	2.8	0.01	
			2.5	2.5	0.01	
			2.8	1.8	0.01	
			4.5	0.9	0.01	

18. V_{CC} is the supply voltage associated with the I/O V_{CC} port, and V_{CC} ranges from +0.9 V to 4.5 V under normal operating conditions.
19. V_L is the supply voltage associated with the I/O V_L port, and V_L ranges from +0.9 V to 4.5 V under normal operating conditions.
20. Typical values are at T_A = +25°C

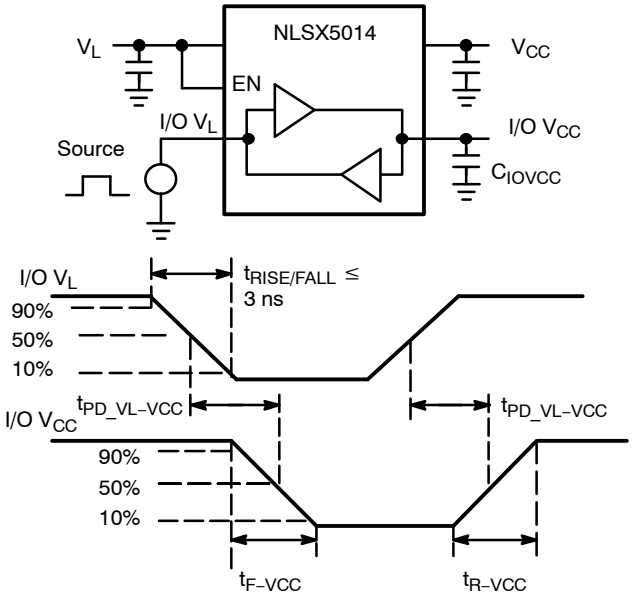


Figure 3. Driving I/O V_L Test Circuit and Timing

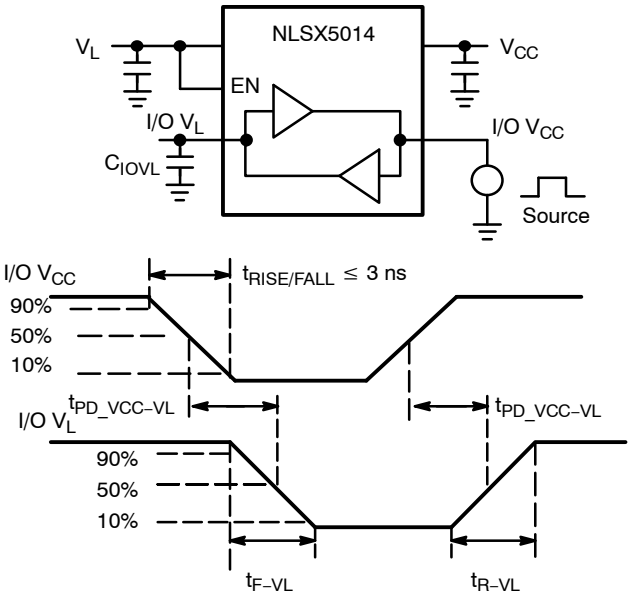
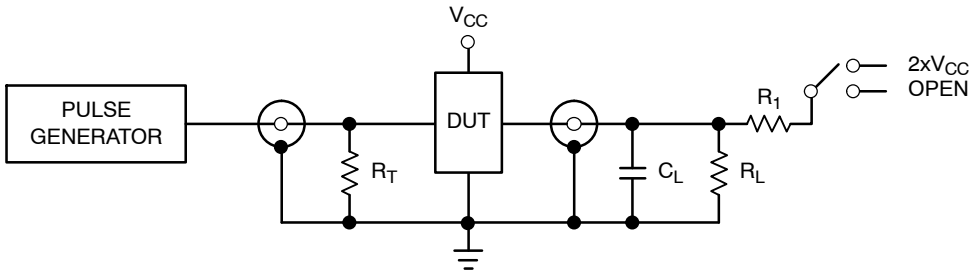


Figure 4. Driving I/O V_{CC} Test Circuit and Timing



Test	Switch
t_{PZH}, t_{PHZ}	Open
t_{PZL}, t_{PLZ}	2 x V_{CC}

C_L = 15 pF or equivalent (Includes jig and probe capacitance)
R_L = R_1 = 50 kΩ or equivalent
R_T = Z_{OUT} of pulse generator (typically 50 Ω)

Figure 5. Test Circuit for Enable/Disable Time Measurement

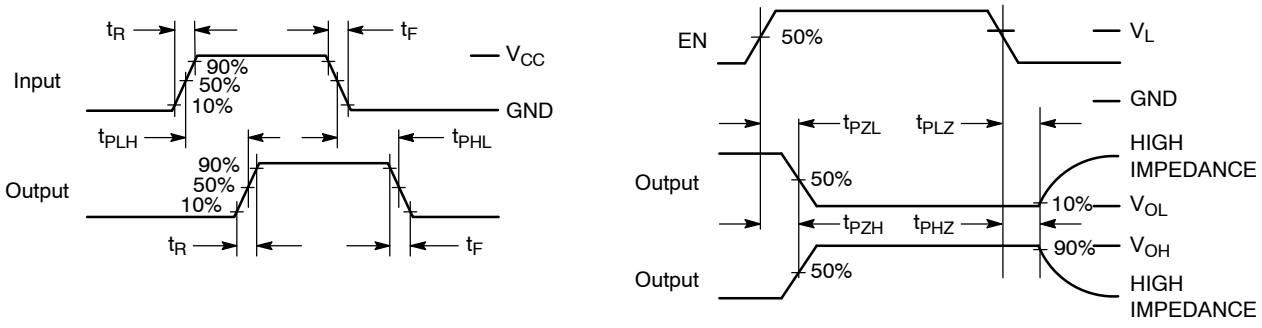


Figure 6. Timing Definitions for Propagation Delays and Enable/Disable Measurement

IMPORTANT APPLICATIONS INFORMATION

Level Translator Architecture

The NLSX5014 auto−sense translator provides bi−directional logic voltage level shifting to transfer data in multiple supply voltage systems. These level translators have two supply voltages, V_L and V_{CC}, which set the logic levels on the input and output sides of the translator. When used to transfer data from the I/O V_L to the I/O V_{CC} ports, input signals referenced to the V_L supply are translated to output signals with a logic level matched to V_{CC}. In a similar manner, the I/O V_{CC} to I/O V_L translation shifts input signals with a logic level compatible to V_{CC} to an output signal matched to V_L.

The NLSX5014 translator consists of bi−directional channels that independently determine the direction of the data flow without requiring a directional pin. One−shot circuits are used to detect the rising or falling input signals. In addition, the one−shots decrease the rise and fall times of the output signal for high−to−low and low−to−high transitions.

Input Driver Requirements

Auto−sense translators such as the NLSX5014 have a wide bandwidth, but a relatively small DC output current rating. The high bandwidth of the bi−directional I/O circuit is used to quickly transform from an input to an output driver and vice versa. The I/O ports have a modest DC current output specification so that the output driver can be over driven when data is sent in the opposite direction. For proper operation, the input driver to the auto−sense translator should be capable of driving 2 mA of peak output current. The bi−directional configuration of the translator results in both input stages being active for a very short time period. Although the peak current from the input signal circuit is relatively large, the average current is small and consistent with a standard CMOS input stage.

Enable Input (EN)

The NLSX5014 translator has an Enable pin (EN) that provides tri−state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O V_{CC} and I/O V_L pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the V_L supply and has Over−Voltage Tolerant (OVT) protection.

Uni−Directional versus Bi−Directional Translation

The NLSX5014 translator can function as a non−inverting uni−directional translator. One advantage of using the translator as a uni−directional device is that each I/O pin can be configured as either an input or output. The configurable input or output feature is especially useful in applications such as SPI that use multiple uni−directional I/O lines to send data to and from a device. The flexible I/O port of the auto sense translator simplifies the trace connections on the PCB.

Power Supply Guidelines

The values of the V_L and V_{CC} supplies can be set to anywhere between 0.9 and 4.5 V. Design flexibility is maximized because V_L may be either greater than or less than the V_{CC} supply. In contrast, the majority of the competitive auto sense translators has a restriction that the value of the V_L supply must be equal to less than (V_{CC} − 0.4) V.

The sequencing of the power supplies will not damage the device during power−up operation. In addition, the I/O V_{CC} and I/O V_L pins are in the high impedance state if either supply voltage is equal to 0 V. For optimal performance, 0.01 to 0.1 μF decoupling capacitors should be used on the V_L and V_{CC} power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

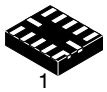
The NLSX5014 translators have a power down feature that provides design flexibility. The output ports are disabled when either power supply is off (V_L or V_{CC} = 0 V). This feature causes all of the I/O pins to be in the power saving high impedance state.

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

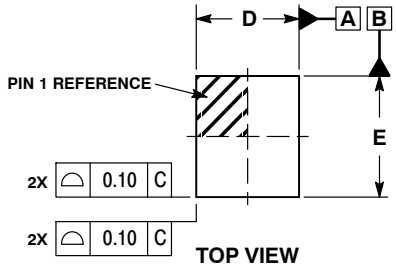
ON Semiconductor®

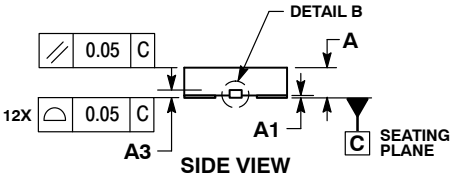
UQFN12 1.7x2.0, 0.4P
CASE 523AE−01
ISSUE A

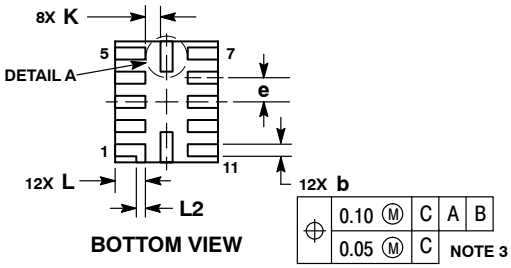
DATE 11 JUN 2007

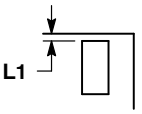


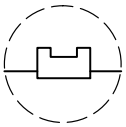
SCALE 4:1











DETAIL B
OPTIONAL CONSTRUCTION

NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30 MM FROM TERMINAL TIP.
4. MOLD FLASH ALLOWED ON TERMINALS ALONG EDGE OF PACKAGE. FLASH 0.03 MAX ON BOTTOM SURFACE OF TERMINALS.
5. DETAIL A SHOWS OPTIONAL CONSTRUCTION FOR TERMINALS.

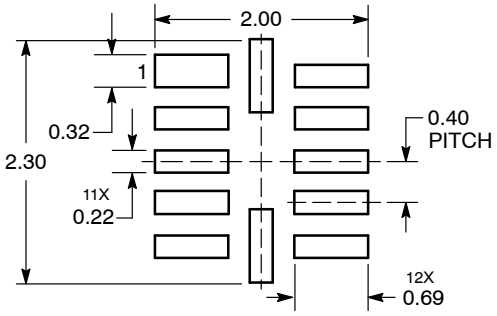
	MILLIMETERS	
DIM	MIN	MAX
A	0.45	0.55
A1	0.00	0.05
A3	0.127 REF	
b	0.15	0.25
D	1.70 BSC	
E	2.00 BSC	
e	0.40 BSC	
K	0.20	----
L	0.45	0.55
L1	0.00	0.03
L2	0.15 REF	

GENERIC MARKING DIAGRAM*

XX = Specific Device Code
M = Date Code
▪ = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “ ▪”, may or may not be present.

MOUNTING FOOTPRINT SOLDERMASK DEFINED

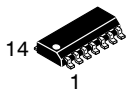


DIMENSIONS: MILLIMETERS

DOCUMENT NUMBER:	98AON23418D	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.	
DESCRIPTION:	UQFN12 1.7 X 2.0, 0.4P		PAGE 1 OF 1

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

ON Semiconductor®



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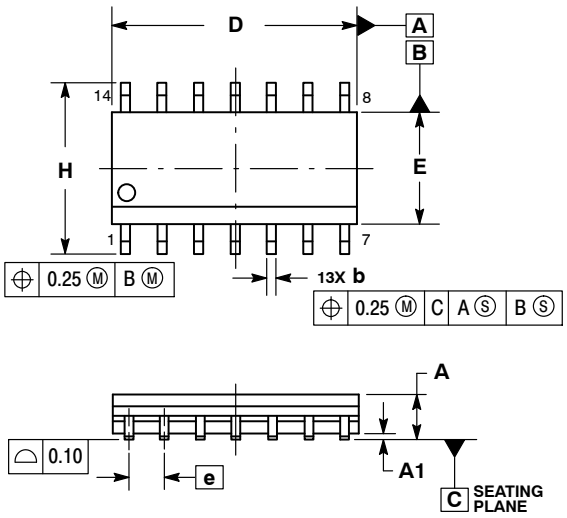
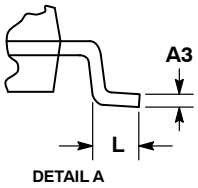
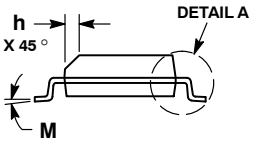
SOIC−14 NB
CASE 751A−03
ISSUE L

DATE 03 FEB 2016



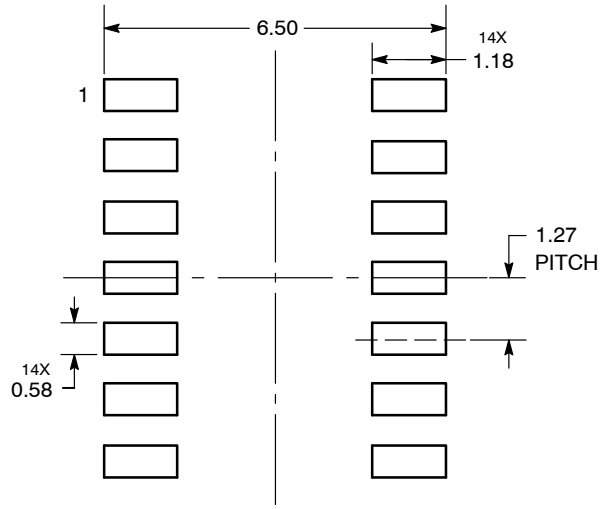




NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
A3	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
M	0 °	7 °	0 °	7 °

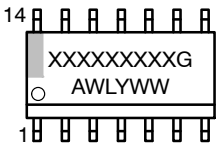
SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
Y = Year
WW = Work Week
G = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “ ▪”, may or may not be present.

STYLES ON PAGE 2

DOCUMENT NUMBER:	98ASB42565B	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.	
DESCRIPTION:	SOIC−14 NB		PAGE 1 OF 2

SOIC−14
CASE 751A−03
ISSUE L

DATE 03 FEB 2016

STYLE 1:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. NO CONNECTION
5. ANODE/CATHODE
6. NO CONNECTION
7. ANODE/CATHODE
8. ANODE/CATHODE
9. ANODE/CATHODE
10. NO CONNECTION
11. ANODE/CATHODE
12. ANODE/CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 2:
CANCELLED

STYLE 3:
PIN 1. NO CONNECTION
2. ANODE
3. ANODE
4. NO CONNECTION
5. ANODE
6. NO CONNECTION
7. ANODE
8. ANODE
9. ANODE
10. NO CONNECTION
11. ANODE
12. ANODE
13. NO CONNECTION
14. COMMON CATHODE

STYLE 4:
PIN 1. NO CONNECTION
2. CATHODE
3. CATHODE
4. NO CONNECTION
5. CATHODE
6. NO CONNECTION
7. CATHODE
8. CATHODE
9. CATHODE
10. NO CONNECTION
11. CATHODE
12. CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 5:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. ANODE/CATHODE
5. ANODE/CATHODE
6. NO CONNECTION
7. COMMON ANODE
8. COMMON CATHODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. ANODE/CATHODE
12. ANODE/CATHODE
13. NO CONNECTION
14. COMMON ANODE

STYLE 6:
PIN 1. CATHODE
2. CATHODE
3. CATHODE
4. CATHODE
5. CATHODE
6. CATHODE
7. CATHODE
8. ANODE
9. ANODE
10. ANODE
11. ANODE
12. ANODE
13. ANODE
14. ANODE

STYLE 7:
PIN 1. ANODE/CATHODE
2. COMMON ANODE
3. COMMON CATHODE
4. ANODE/CATHODE
5. ANODE/CATHODE
6. ANODE/CATHODE
7. ANODE/CATHODE
8. ANODE/CATHODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. COMMON CATHODE
12. COMMON ANODE
13. ANODE/CATHODE
14. ANODE/CATHODE

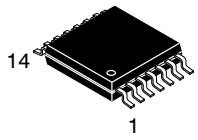
STYLE 8:
PIN 1. COMMON CATHODE
2. ANODE/CATHODE
3. ANODE/CATHODE
4. NO CONNECTION
5. ANODE/CATHODE
6. ANODE/CATHODE
7. COMMON ANODE
8. COMMON ANODE
9. ANODE/CATHODE
10. ANODE/CATHODE
11. NO CONNECTION
12. ANODE/CATHODE
13. ANODE/CATHODE
14. COMMON CATHODE

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

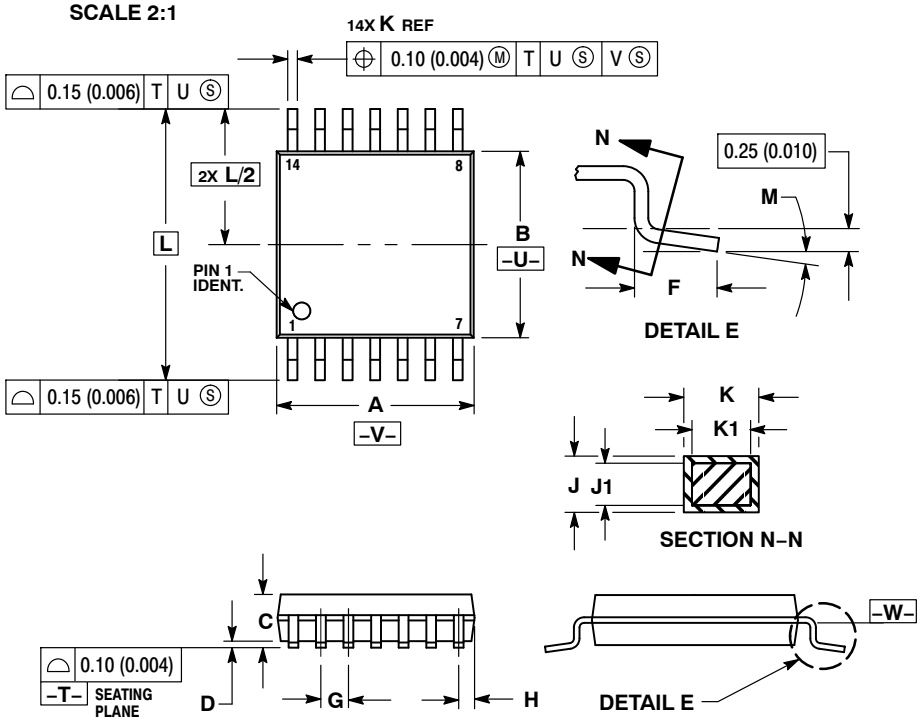
ON Semiconductor®

TSSOP−14 WB
CASE 948G
ISSUE C

DATE 17 FEB 2016



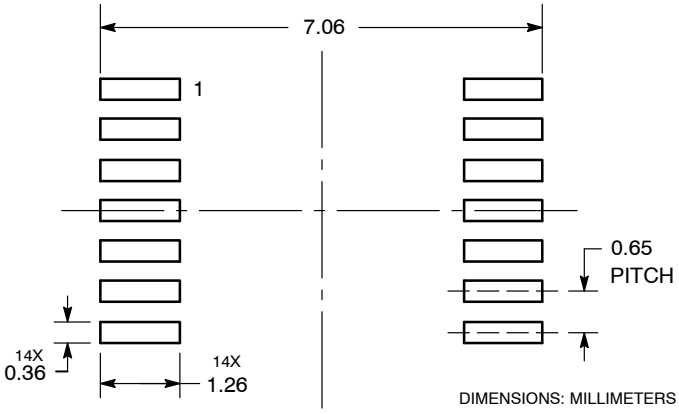
SCALE 2:1



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE −W−.

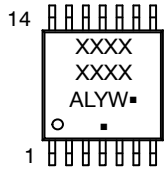
	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	4.90	5.10	0.193	0.200
B	4.30	4.50	0.169	0.177
C	−−−	1.20	−−−	0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
H	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
M	0 °	8 °	0 °	8 °

SOLDERING FOOTPRINT



DIMENSIONS: MILLIMETERS

GENERIC MARKING DIAGRAM*



A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
▪ = Pb−Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “ ▪”, may or may not be present.

DOCUMENT NUMBER:	**98ASH70246A**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped “CONTROLLED COPY” in red.
DESCRIPTION:	**TSSOP−14 WB**	**PAGE 1 OF 1**